

Michael Deveaux

Monolithic Active Pixel Sensors (MAPS)

For Heavy Ion Experiments

Outline:

- CBM demands \Leftrightarrow Pixel detector performances
- Operating principle of MAPS
- Features of MAPS
- Development status report (thinning, radiation hardness, readout-speed)

Performances of different pixel-detectors

Comparing MAPS and established pixel-detectors

CBM demands (preliminary)fulfilled?	Hybrid pixels	CCDs	MAPS
Single point resolution	No	Yes	Yes
Material budget	No	Yes	Yes
Time resolution	Yes	No	No
Radiation hardness	No	No	No

What stands MAPS for?

Monolithic:

Readout-electronics and sensors are integrated on the same substrate.

Active Pixel :

Signal processing microcircuits are integrated in each pixel.

Sensor

MAPS were developed for visible light applications by industry.

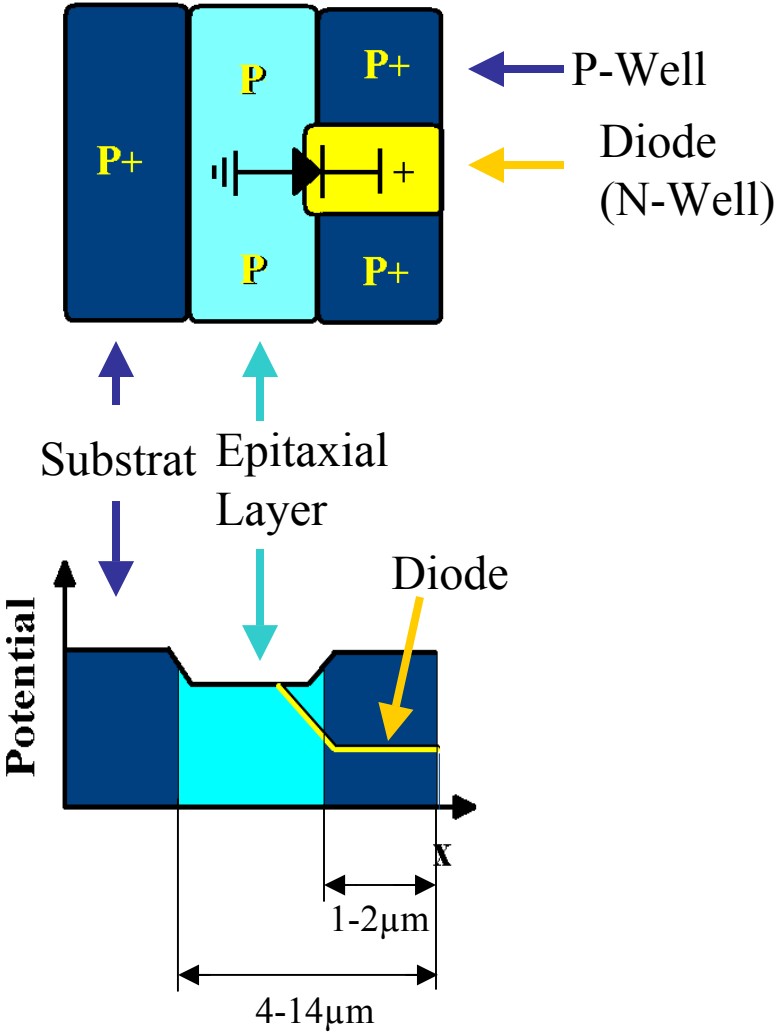
MAPS may be produced with standard CMOS-processes.

R&D for application on Futur Linear Collider since 1999 @ IReS

The operation principle of MAPS

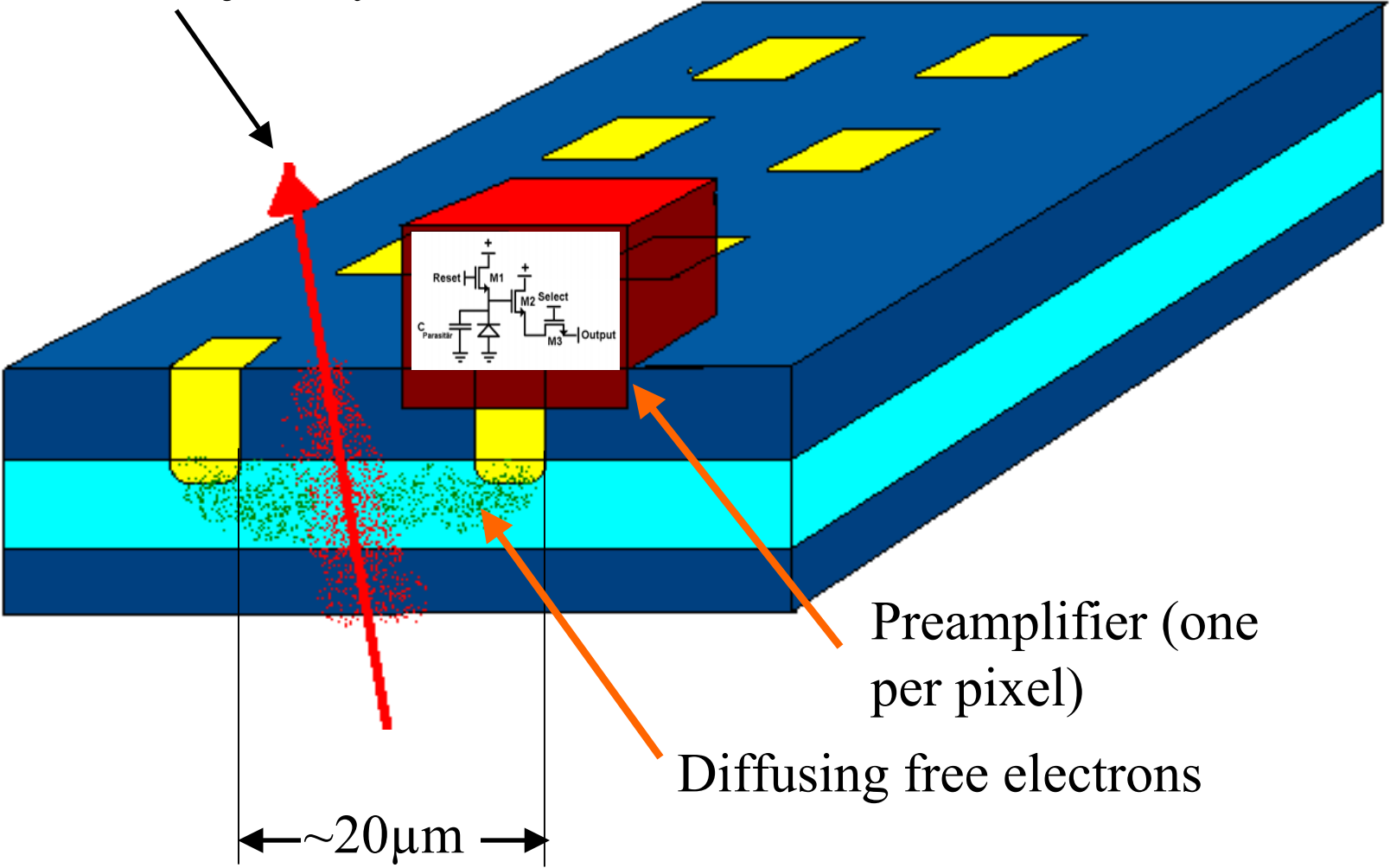
Sensor design:

A
Minimum
Ionising
Particle creates
about 80 e⁻/h⁺-pairs
per μm in Si



The operation principle of MAPS

Particle trajectory

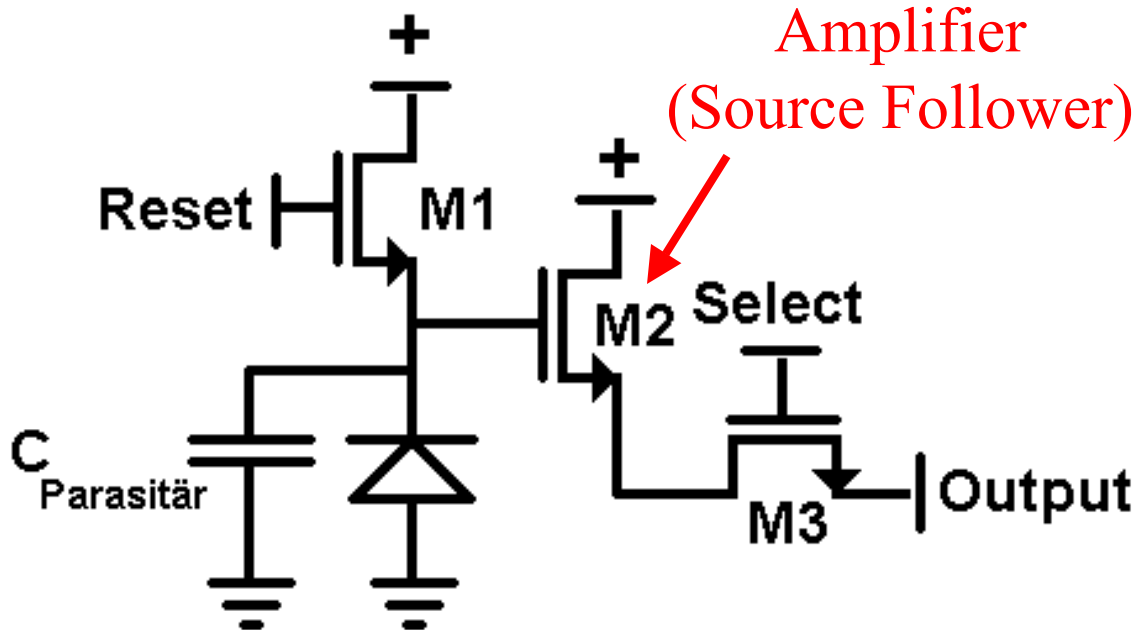


Preamplifier (one per pixel)

Diffusing free electrons

$\sim 20\mu\text{m}$

The operation principle of MAPS



Layout of a classical Active Pixel (simplified)

The MIMOSA - technologie

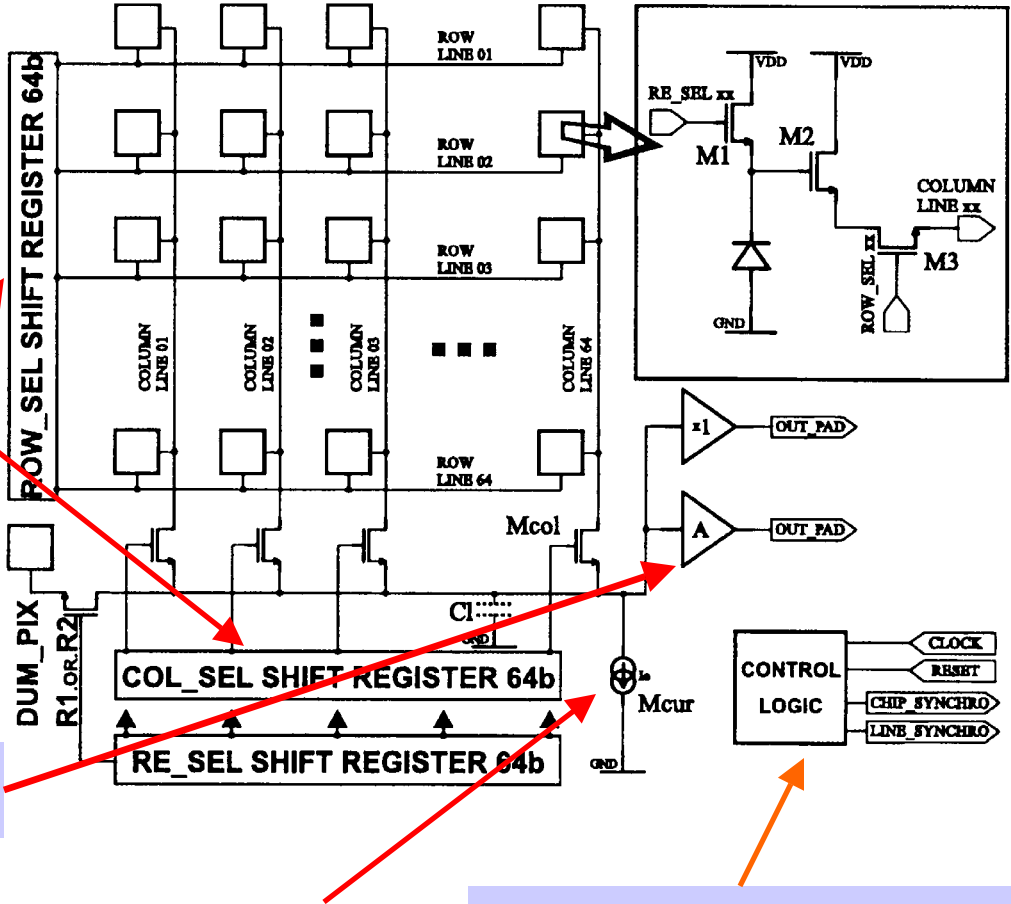
Chip layout:

X- and Y-shift registers to select pixels.

Common amplifier

Current source

IO-Signals needed:
Clock, Reset, Synchro
and analog out

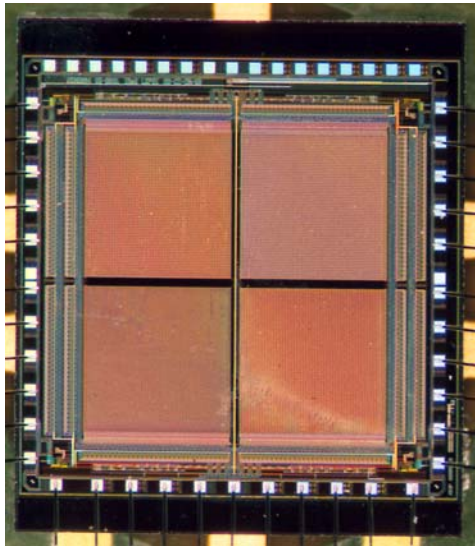


The MIMOSA - Technology

Minimum Ionizing Particle MOS Active Pixel Sensor

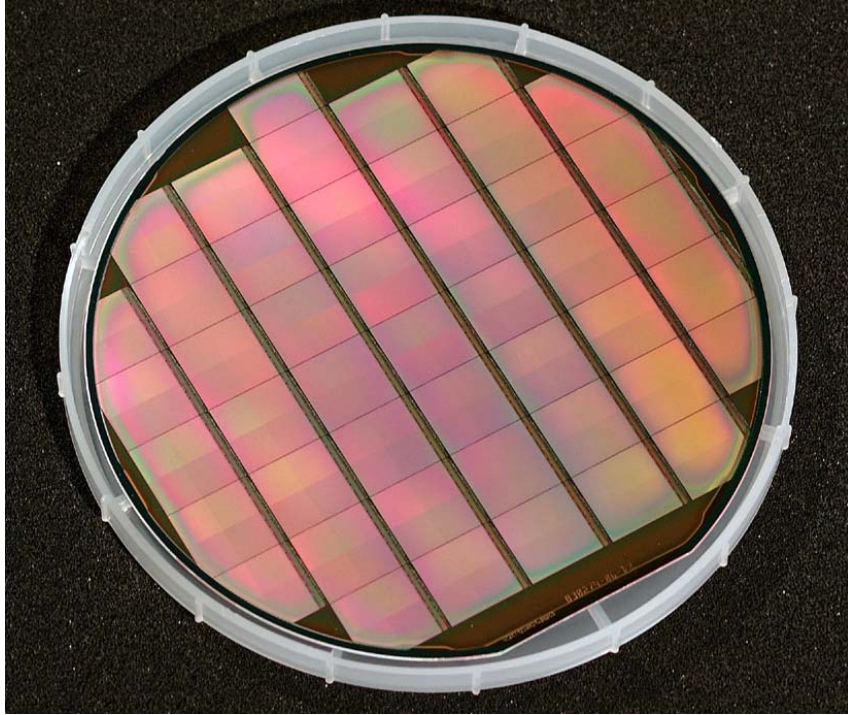
Features of the MIMOSA (I – VI) – detectors:

- Single track resolution $1.3\mu\text{m} - 3\mu\text{m}$
- Typical Pixel – pitch $20\mu\text{m}$
- Thinning potentially possible down to $\sim 20\mu\text{m}$
- S/N for MIPs 20 – 40
- Readout speed: 10MPixel/s (design: 40MPix/s)
- Design tested on different commercially available CMOS-Processes
- 1k€ per 10^6 Pixel (Prototype)



MIMOSA IV

Status and plans: Thinning



MIMOSA V Wafer

Goal:

$\approx 50\mu\text{m}/\text{sensor}$

Present:

MIMOSA V (1MPixel / $3,5\text{cm}^2$)
thinned down to $120\mu\text{m}$

Near futur:

Industrial thinning of MIMOSA V
wafers to

$\sim (15\mu\text{m Sensor} + 25\mu\text{m support}).$

Status and plans: Radiation hardness (ionizing)

Degradations occur after a few 100 kRad
(checked with β , X-rays)

Behavior observed after 200kRad X-rays:

MIMOSA II:

- **strong charge loss.**
- **Gain not degraded and constant.**

MIMOSA IV:

- **No charge loss.**
- **Gain slightly degraded and depending on temperature.**
- **Reasons for degradations mostly understood.**

Small changes in design improve the radiation hardness
=> more detailed understanding of design is necessary

Status and plans: Radiation hardness (ionizing)

Origin of weak points is under study:

- I -V and C -V measurements were done to learn about process parameters (doping profile...).
- Results are to be used as input for ISE-TCAD simulations.
- Test structures are implemented in current and future chips.
- First updated designs basing on preliminary understanding are implemented on new chips (Tests underway).

Status and plans: Radiation hardness (neutrons)

Charge losses occur for fluences higher than $\sim 10^{12} \text{ n}_{\text{eq}}/\text{cm}^2$

Main problem:

Defect states in band gap (traps).

=> Decrease of charge carriers lifetime.

=> Decrease of charge collection and signal.

Standard approach (LHC):

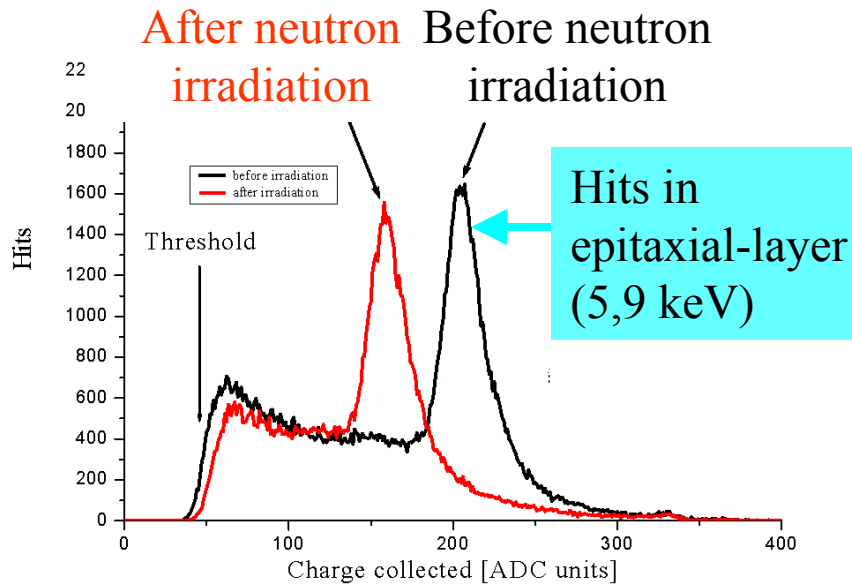
- Using depleted devices for fast charge collection.

Not compatible with industrial CMOS-processes.

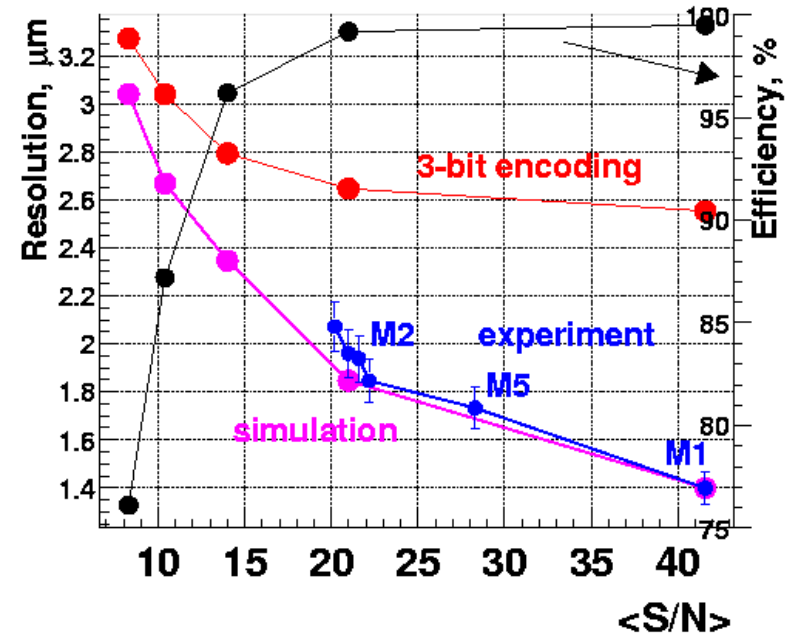
=> **New ways are to be found**

Status and plans: Radiation hardness (neutrons)

Charge collected



S/N versus resolution



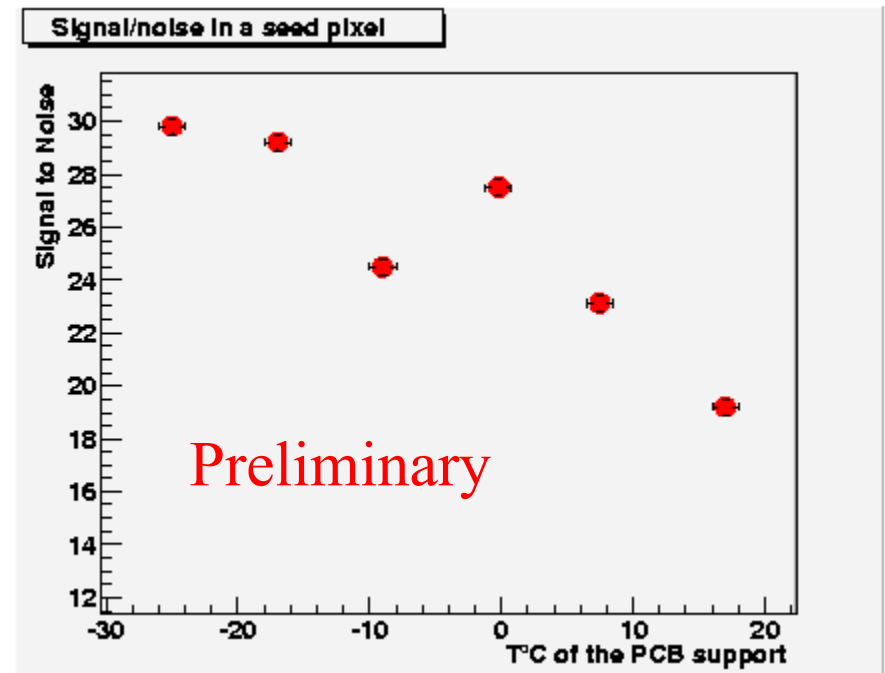
- Pixels loose S/N \Rightarrow drop in detection efficiency.
- Readout electronics stays ok \Rightarrow Pixels die individually
- Resolution stays ok.

Status and plans: Radiation hardness (neutrons)

Approaches to be evaluated:

- Optimised pixel geometry (ISE -TCAD – Simulation)
- Temperature dependence of charge losses (Lazarus effect) →
- Using sensors with better intrinsic S/N (PhotoFET)

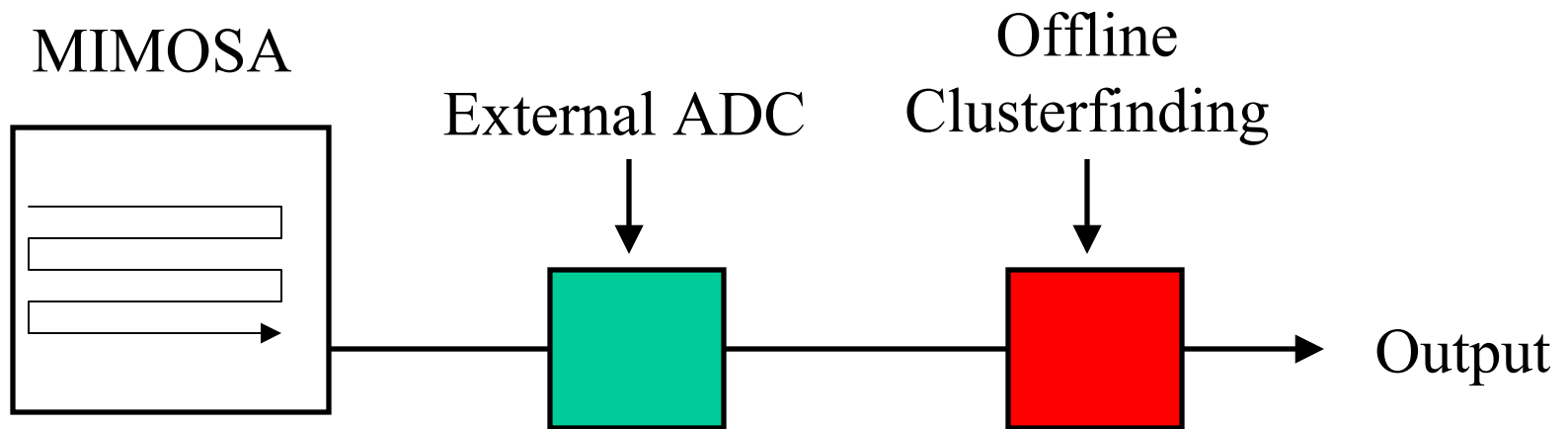
MIMOSA IV after $1.4 \cdot 10^{11} n_{eq}/cm^2$.
S/N in a seed pixel



Simple and relatively cheap approach to gain a factor 10-100:
Replacing the damaged area for example every month.

Status and plans: Readout speed

MIMOSA V needs ~ 6 ms for serial readout (1MPixel).



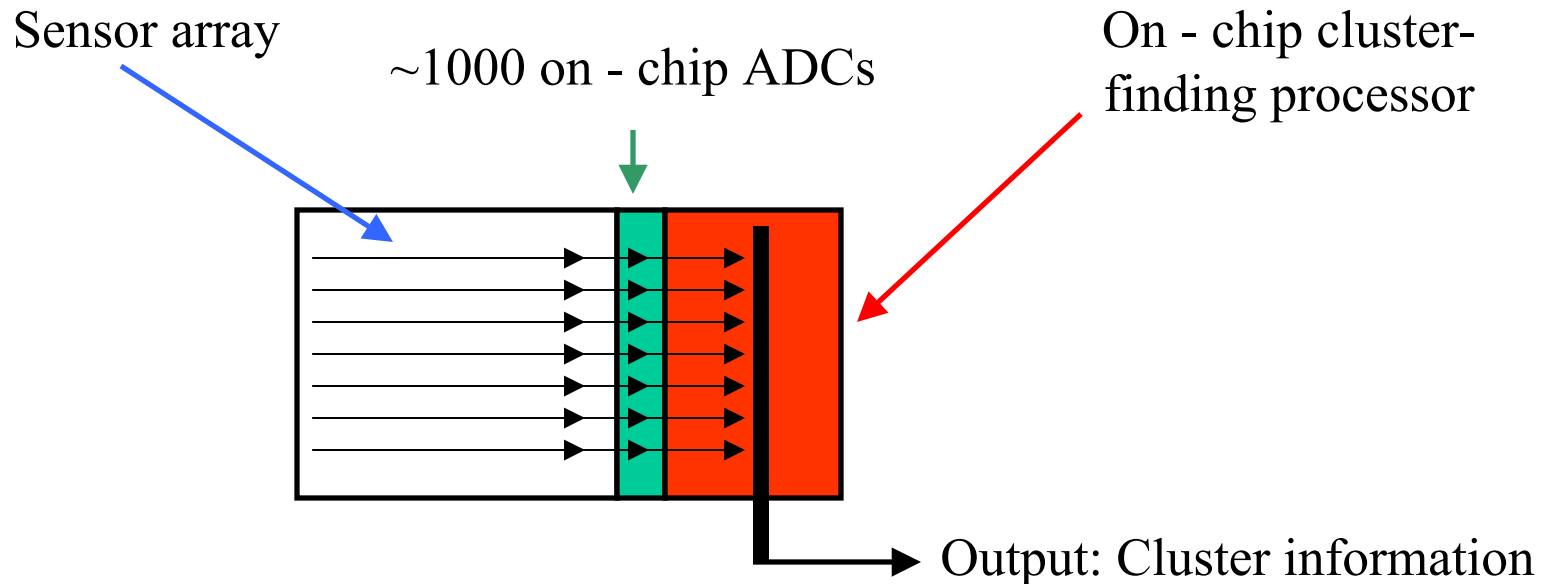
~ 40 Mpixel /s per analog output-line is possible

A factor 100 - 1000 may be won using a column parallel readout.

~ 100 GB / s dataflow for **1MPixel** is expected for $10\mu\text{s}/\text{frame}$

Status and plans: Readout speed

Approach: On-chip real time data sparcification.



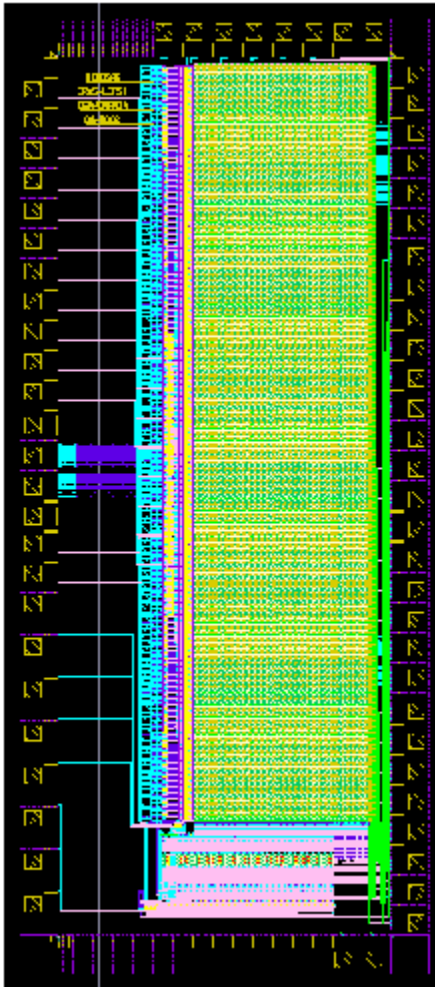
A CDS-Processor + memory must be included in each pixel

=> Individual pixel readout drops to ~10MHz

Goals: 250 μ s/frame in a first step, 10 μ s/frame within three years.

Status and plans: Readout speed

First prototype with column parallel readout: MIMOSA VI



In every pixel (28 μ m pitch):

- Additional amplification (5.5x)
- Analogue CDS processing
- 29 transistors, 3 capacitors

In every column:

- Discriminator

- 30 columns (128 Pixels each) with parallel readout
- 30MHz clock, 5MHz readout (6 clocks per pixel)

Tests under way

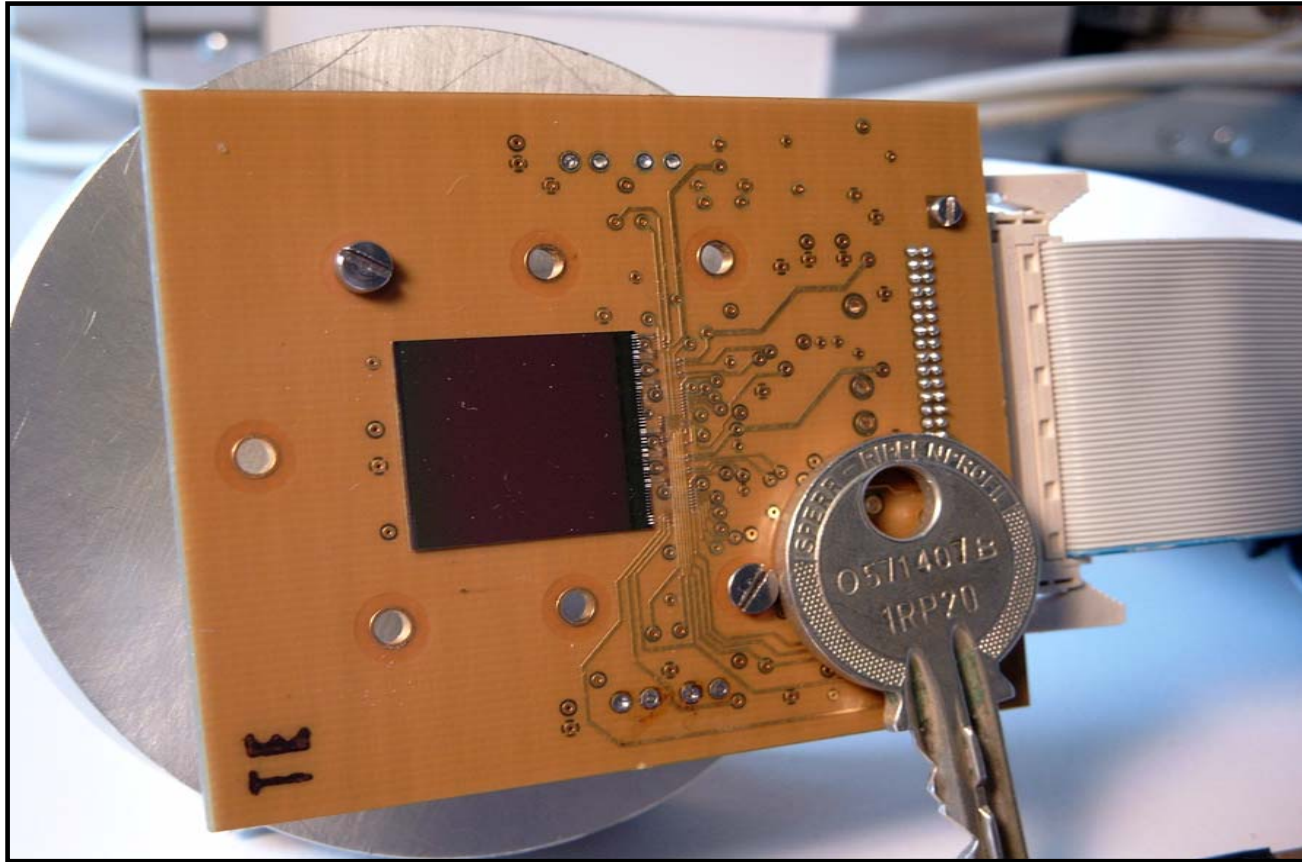
Summary

- **A single track resolution of $1.3\mu\text{m}$ - $3\mu\text{m}$ has been demonstrated for MAPS.**
- **Industrial thinning to $\sim (15\mu\text{m} + 25\mu\text{m})$ in near future**
- **Column parallel readout should enable $10\mu\text{s}$ time-resolution in three years.**

Intensive radiation hardness studies are underway

- **detailed understanding of design for further improvement concerning ionising radiation**
- **evaluation of new approaches concerning neutron radiation (optimised geometry, low temperature...)**

Thank you



MIMOSA V

More information in the internet:

<http://ireswww.in2p3.fr/ires/recherche/capteurs/index.html>